

# 1200 V 135 mΩ SiC MOSFET

## Silicon Carbide MOSFET

Trench-Assisted Planar Technology

$V_{DS}$	=	1200 V
$R_{DS(ON)}$ (Typ.)	=	135mΩ
$I_D$ ( $T_C = 100^\circ\text{C}$ )	=	13 A

### Features

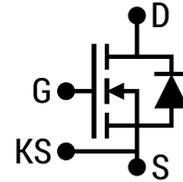
- Gen3F (3rd Generation) Technology
- Most Stable  $R_{DS(ON)}$  over Temperature
- Low  $C_{OSS}$ ,  $C_{RSS}$  and Balanced  $C_{ISS}/C_{RSS}$
- Lower  $Q_{GD}$  and Balanced  $R_{G(INT)}$
- Electromagnetically Optimized Design
- Robust Body Diode with Low  $V_F$  and Low  $Q_{RR}$
- 100% Avalanche (UIL) Tested
- AEC-Q101 Qualified

### Package

Case (D)



TO-263-7



D = Drain  
G = Gate  
S = Source  
KS = Kelvin Source



### Advantages

- Superior Performance and Robustness
- Lowest Conduction Losses at all Temperatures
- Lesser Switching Spikes and Lower Losses
- Faster and More Efficient Switching
- Reduced Ringing
- Ease of Paralleling without Thermal Runaway
- Excellent Power Density and System Efficiency
- Enhanced System Reliability

### Applications

- xEV - DC-DC
- Solar / PV
- Energy Storage Systems
- Uninterruptible Power Supply
- Motor Control

### Absolute Maximum Ratings (At $T_C = 25^\circ\text{C}$ Unless Otherwise Stated)

Parameter	Symbol	Conditions	Values	Unit	Note
Drain-Source Voltage	$V_{DS(max)}$	$V_{GS} = 0\text{ V}, I_D = 100\ \mu\text{A}$	1200	V	
Gate-Source Voltage (Dynamic)	$V_{GS(max)}$		-10 / +22	V	
Gate-Source Voltage (Static)	$V_{GS(op)-ON}$	Recommended Operation	18	V	Note 1
	$V_{GS(op)-OFF}$		-5 to -3		
Continuous Drain Current	$I_D$	$T_C = 25^\circ\text{C}, V_{GS} = -5 / +18\text{ V}$	18	A	Fig. 16
		$T_C = 100^\circ\text{C}, V_{GS} = -5 / +18\text{ V}$	13		
		$T_C = 135^\circ\text{C}, V_{GS} = -5 / +18\text{ V}$	9		
Pulsed Drain Current	$I_{D(pulse)}$	$t_p \leq 3\ \mu\text{s}, D \leq 1\%, V_{GS} = 18\text{ V}$	48	A	Note 2
Power Dissipation	$P_D$	$T_C = 25^\circ\text{C}$	87	W	Fig. 17
Non-Repetitive Avalanche Energy	$E_{AS}$	$L = 36\text{ mH}, I_{AV} = 2\text{ A}$	72	mJ	
Operating Junction and Storage Temperature	$T_j, T_{stg}$		-55 to 175	$^\circ\text{C}$	

Note 1: This product can support 0V turn-off gate drive voltage with optimized PCB layout and gate drive circuit configuration.

Note 2: Pulse Width  $t_p$  Limited by  $T_{j(max)}$

Electrical Characteristics (At  $T_C = 25^\circ\text{C}$  Unless Otherwise Stated)

Parameter	Symbol	Conditions	Values			Unit	Note
			Min.	Typ.	Max.		
Drain-Source Breakdown Voltage	$V_{DSS}$	$V_{GS} = 0\text{ V}, I_D = 100\ \mu\text{A}$	1200			V	
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = 1200\text{ V}, V_{GS} = 0\text{ V}$		1	50	$\mu\text{A}$	
Gate Source Leakage Current	$I_{GSS}$	$V_{DS} = 0\text{ V}, V_{GS} = 22\text{ V}$ $V_{DS} = 0\text{ V}, V_{GS} = -10\text{ V}$			100 -100	nA	
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 5\text{ mA}$	2.2	3.1	4.3	V	Note 3
Transconductance	$g_{fs}$	$V_{DS} = 10\text{ V}, I_D = 8\text{ A}$ $V_{DS} = 10\text{ V}, I_D = 8\text{ A}, T_j = 175^\circ\text{C}$		4.4 4.3		S	Fig. 5
Drain-Source On-State Resistance	$R_{DS(on)}$	$V_{GS} = 18\text{ V}, I_D = 8\text{ A}$ $V_{GS} = 18\text{ V}, I_D = 8\text{ A}, T_j = 175^\circ\text{C}$		135 245	180	m $\Omega$	Fig. 6-9
Input Capacitance	$C_{iss}$			575			
Output Capacitance	$C_{oss}$			26		pF	Fig. 12
Reverse Transfer Capacitance	$C_{rss}$			2.5			
$C_{oss}$ Stored Energy	$E_{oss}$	$V_{DS} = 800\text{ V}, V_{GS} = 0\text{ V}$		10		$\mu\text{J}$	Fig. 13
$C_{oss}$ Stored Charge	$Q_{oss}$	$f = 500\text{ KHz}, V_{AC} = 25\text{ mV}$		37		nC	
Effective Output Capacitance (Energy Related)	$C_{o(er)}$			31		pF	Note 4
Effective Output Capacitance (Time Related)	$C_{o(tr)}$			46			
Gate-Source Charge	$Q_{gs}$	$V_{DS} = 800\text{ V}, V_{GS} = -5 / +18\text{ V}$		7			
Gate-Drain Charge	$Q_{gd}$	$I_D = 8\text{ A}$		7		nC	Fig. 11
Total Gate Charge	$Q_g$	Per JEDEC JEP-192		27			
Internal Gate Resistance	$R_{G(int)}$	$V_{GS} = 18\text{ V}, f = 1\text{ MHz}, V_{AC} = 25\text{ mV}$		1.3		$\Omega$	
Turn-On Switching Energy (Body Diode)	$E_{on}$	$T_j = 25^\circ\text{C}, V_{GS} = -5/+18\text{ V}, R_{G(ext)} = 10\ \Omega, L = 160.0\ \mu\text{H}, I_D = 8\text{ A}, V_{DD} = 800\text{ V}$		53		$\mu\text{J}$	Fig. 24-27
Turn-Off Switching Energy (Body Diode)	$E_{off}$			10			
Turn-On Delay Time	$t_{d(on)}$			13			
Rise Time	$t_r$	$V_{DD} = 800\text{ V}, V_{GS} = -5/+18\text{ V}$		8			
Turn-Off Delay Time	$t_{d(off)}$	$R_{G(ext)} = 10\ \Omega, L = 160.0\ \mu\text{H}, I_D = 8\text{ A}$		14		ns	Fig. 26
Fall Time	$t_f$	Timing relative to $V_{DS}$ , Inductive load		7			

Note 3: Tested after applying 30ms pulse at  $V_{GS} = +25\text{V}$

Note 4:  $C_{o(er)}$ , a lumped capacitance that gives same stored energy as  $C_{oss}$  while  $V_{DS}$  is rising from 0 to 800V.

$C_{o(tr)}$ , a lumped capacitance that gives same charging times as  $C_{oss}$  while  $V_{DS}$  is rising from 0 to 800V.

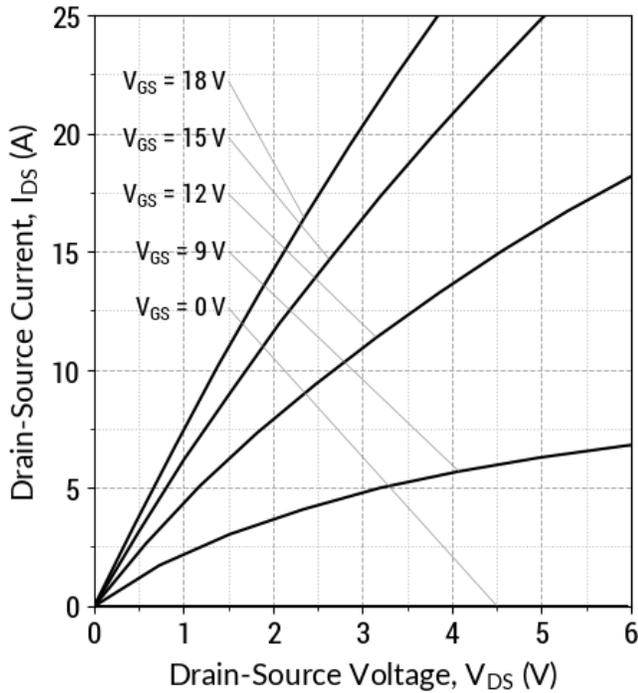
**Reverse Diode Characteristics**

Parameter	Symbol	Conditions	Values			Unit	Note
			Min.	Typ.	Max.		
Diode Forward Voltage	$V_{SD}$	$V_{GS} = -5\text{ V}, I_{SD} = 4\text{ A}$		4.4		V	Fig. 18-19
		$V_{GS} = -5\text{ V}, I_{SD} = 4\text{ A}, T_j = 175^\circ\text{C}$		3.9			
Continuous Diode Forward Current	$I_S$	$V_{GS} = -5\text{ V}, T_c = 25^\circ\text{C}$			13	A	
		$V_{GS} = -5\text{ V}, T_c = 100^\circ\text{C}$			8		
Diode Pulse Current	$I_{S(pulse)}$	$V_{GS} = -5\text{ V}$		32		A	Note 2
Reverse Recovery Time	$t_{rr}$			14		ns	
Reverse Recovery Charge	$Q_{rr}$	$V_{GS} = -5\text{ V}, I_{SD} = 8\text{ A}, V_R = 800\text{ V}$ $dif/dt = 2000\text{ A}/\mu\text{s}, T_j = 25^\circ\text{C}$		30		nC	
Peak Reverse Recovery Current	$I_{rm}$			2.3		A	
Reverse Recovery Time	$t_{rr}$			22		ns	
Reverse Recovery Charge	$Q_{rr}$	$V_{GS} = -5\text{ V}, I_{SD} = 8\text{ A}, V_R = 800\text{ V}$ $dif/dt = 2000\text{ A}/\mu\text{s}, T_j = 175^\circ\text{C}$		75		nC	
Peak Reverse Recovery Current	$I_{rm}$			3		A	

**Package Characteristics**

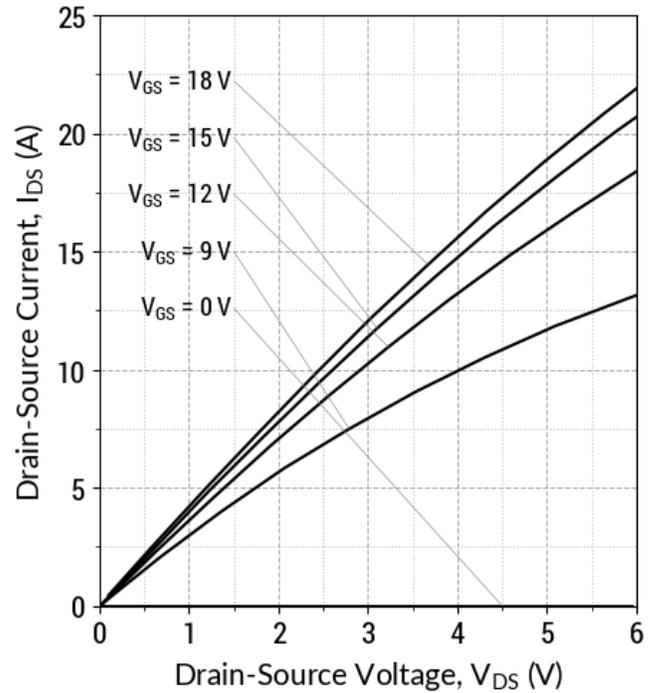
Parameter	Symbol	Conditions	Values	Unit	Note
Max Thermal Resistance, Junction - Case	$R_{thJC-Max}$	Maximum	1.73	$^\circ\text{C}/\text{W}$	Fig. 14
Weight	$W_T$		1.45	g	
Moisture Sensitivity Level	MSL		1		
EMC Material Group			II		

Fig 1: Typical Output Characteristics ( $T_j = 25^\circ\text{C}$ )



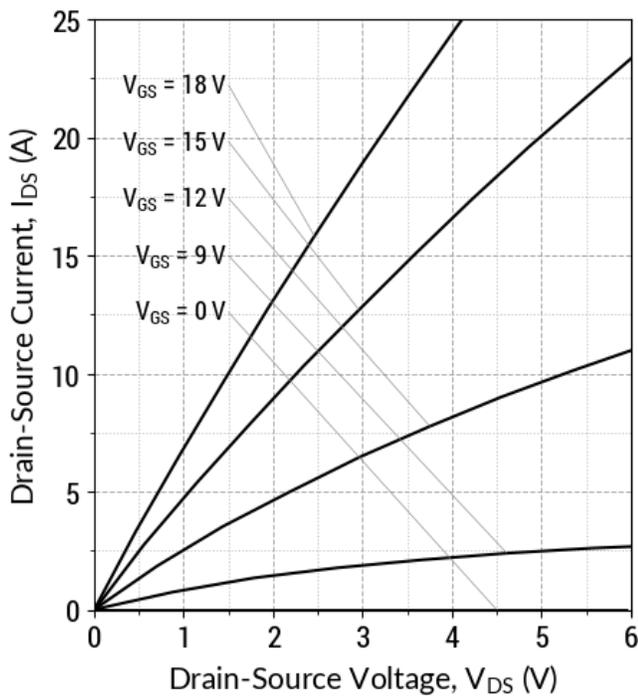
$I_D = f(V_{DS}, V_{GS}); t_P = 50 \mu\text{s}$

Fig 2: Typical Output Characteristics ( $T_j = 175^\circ\text{C}$ )



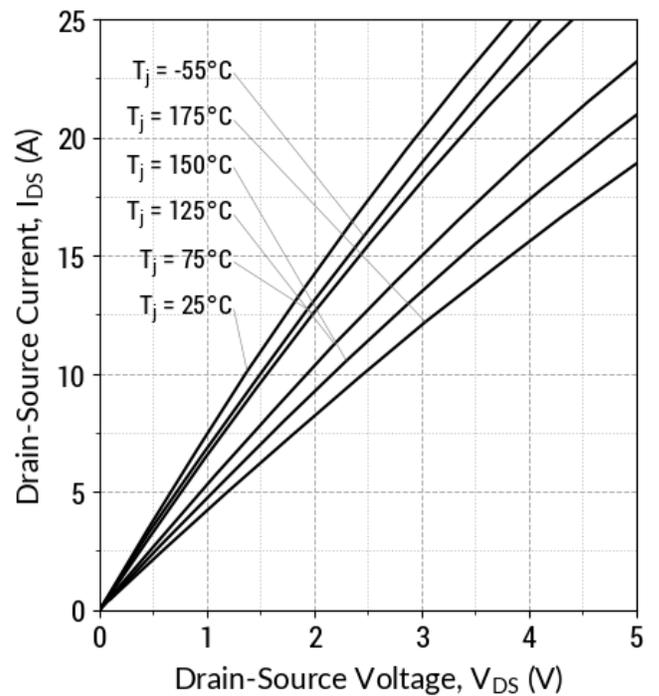
$I_D = f(V_{DS}, V_{GS}); t_P = 50 \mu\text{s}$

Fig 3: Typical Output Characteristics ( $T_j = -55^\circ\text{C}$ )



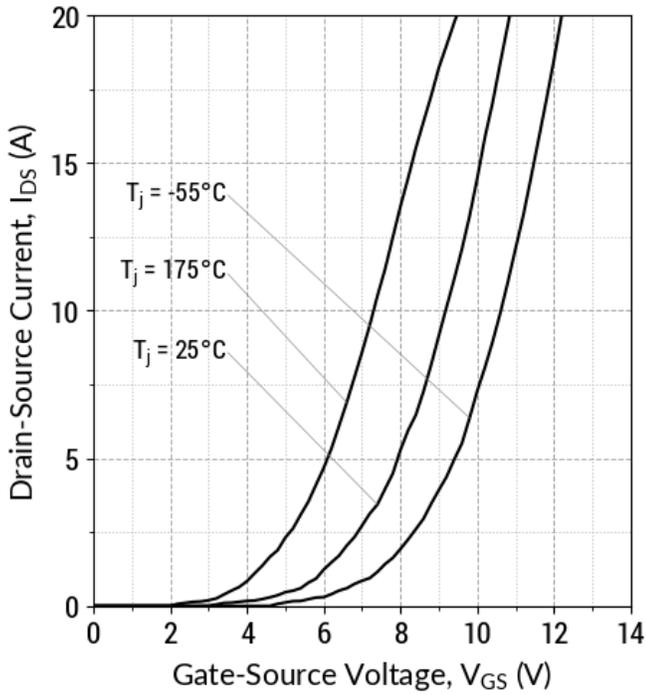
$I_D = f(V_{DS}, V_{GS}); t_P = 50 \mu\text{s}$

Fig 4: Typical Output Characteristics ( $V_{GS} = 18\text{V}$ )



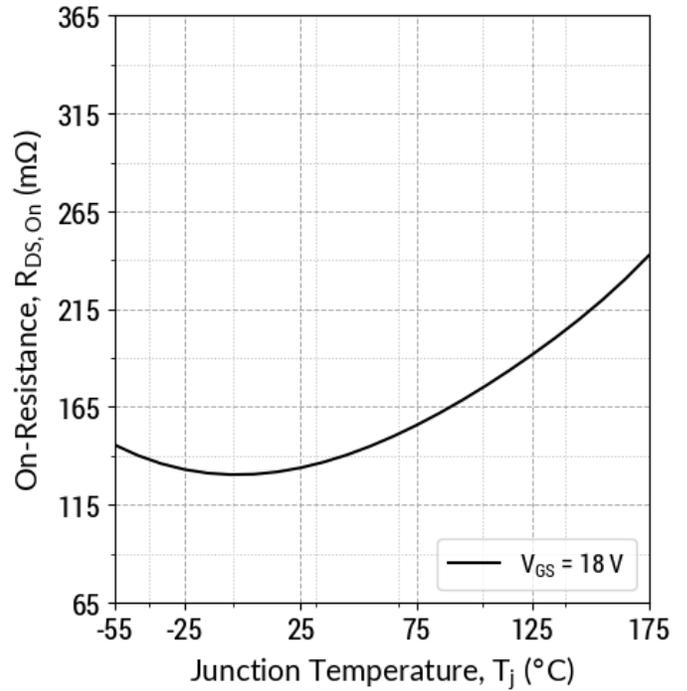
$I_D = f(V_{DS}, T_j); t_P = 50 \mu\text{s}$

Fig 5: Typical Transfer Characteristics ( $V_{DS} = 10\text{ V}$ )



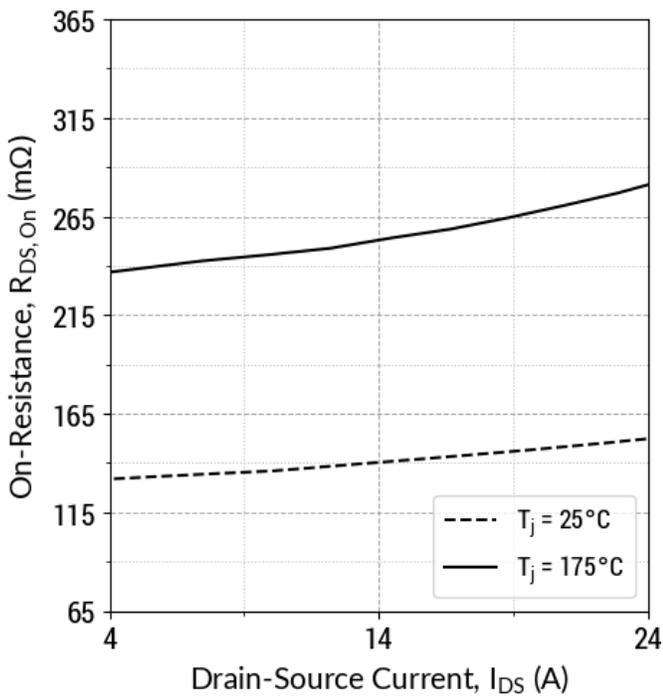
$I_D = f(V_{GS}, T_j); t_p = 100\ \mu\text{s}$

Fig 6: Typical  $R_{DS(ON)}$  v/s Temperature



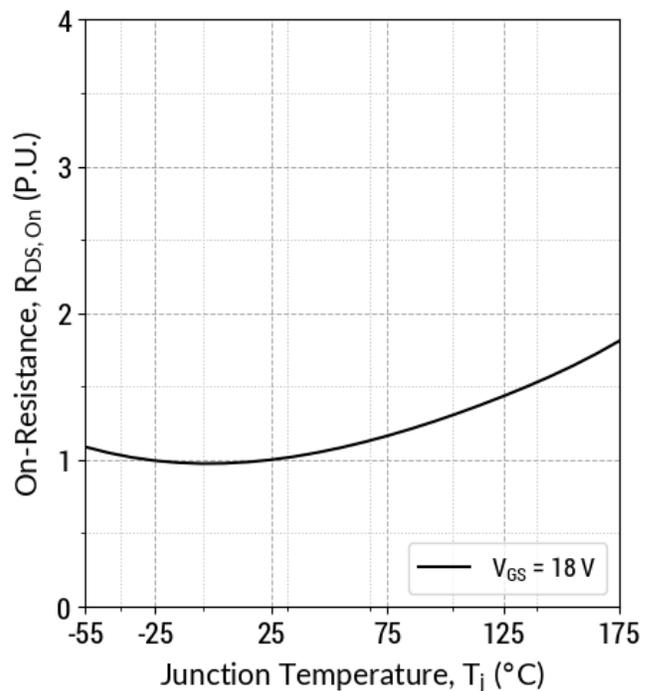
$R_{DS(ON)} = f(T_j, V_{GS}); t_p = 50\ \mu\text{s}; I_D = 8\text{ A}$

Fig 7: Typical  $R_{DS(ON)}$  v/s Drain Current



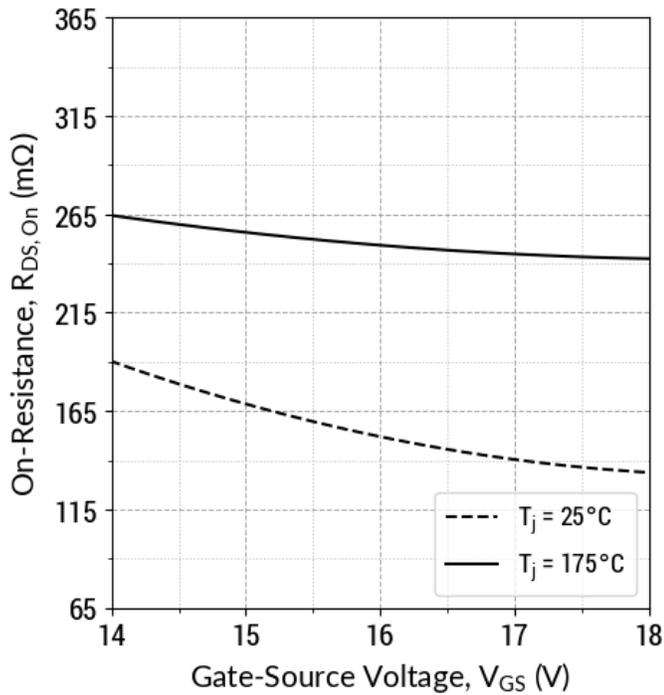
$R_{DS(ON)} = f(T_j, I_D); t_p = 50\ \mu\text{s}; V_{GS} = 18\text{ V}$

Fig 8: Typical Normalized  $R_{DS(ON)}$  v/s Temperature



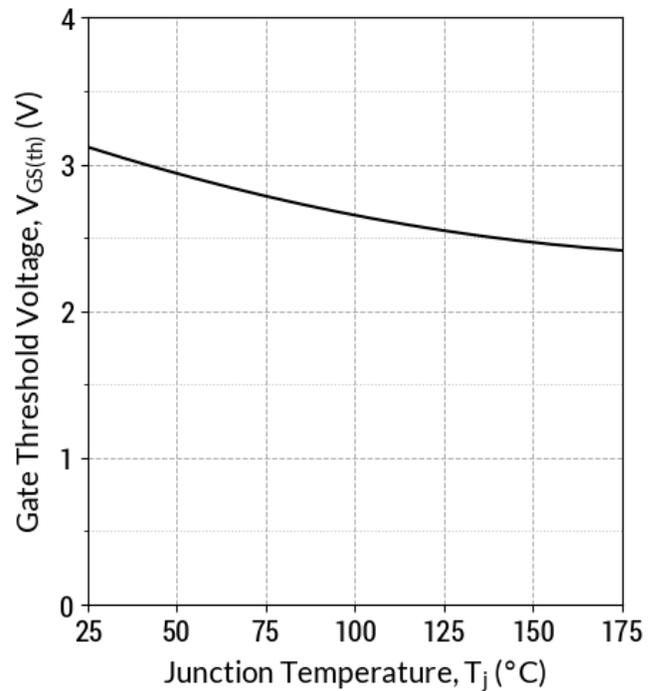
$R_{DS(ON)} = f(T_j); t_p = 50\ \mu\text{s}; I_D = 8\text{ A}$

Fig 9: Typical  $R_{DS(ON)}$  v/s Gate Voltage



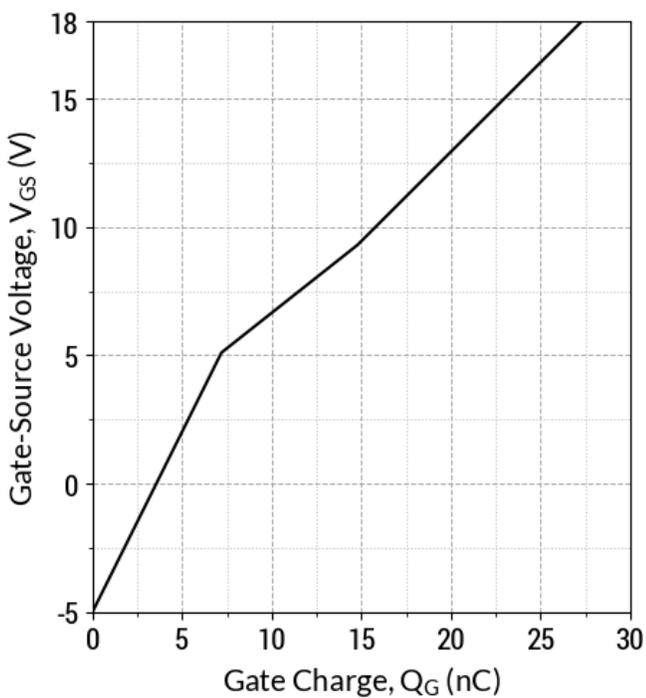
$R_{DS(ON)} = f(T_j, V_{GS}); t_P = 50 \mu\text{s}; I_D = 8 \text{ A}$

Fig 10: Typical Threshold Voltage Characteristics



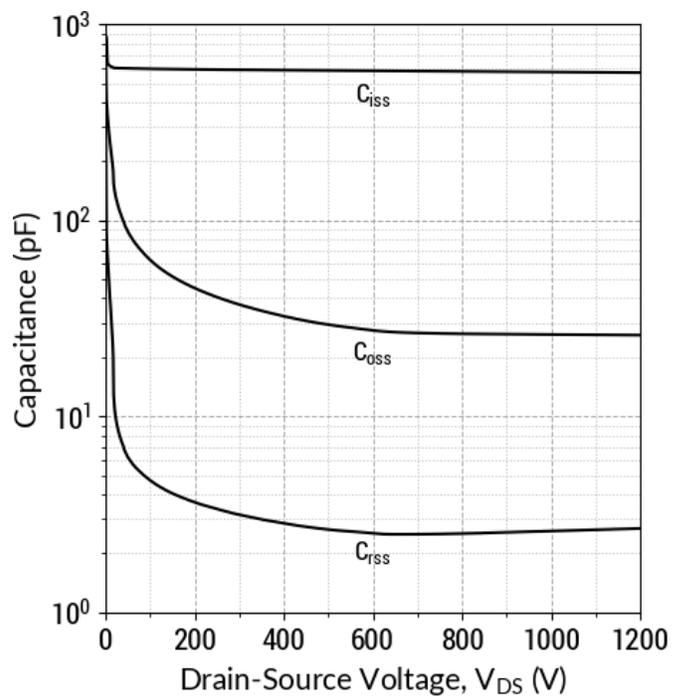
$V_{GS(th)} = f(T_j); V_{DS} = V_{GS}; I_D = 5 \text{ mA}$

Fig 11: Typical Gate Charge Characteristics



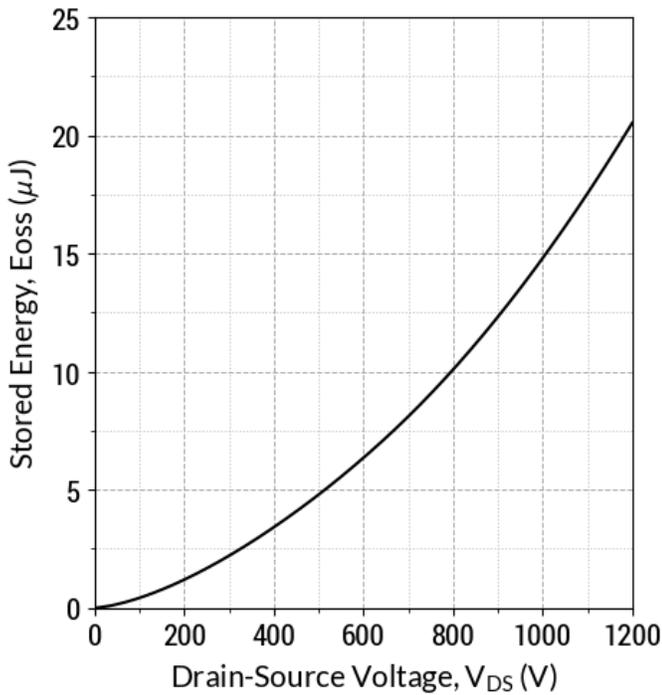
$I_D = 8 \text{ A}; V_{DS} = 800 \text{ V}; T_c = 25^\circ\text{C}$

Fig 12: Typical Capacitance v/s Drain-Source Voltage



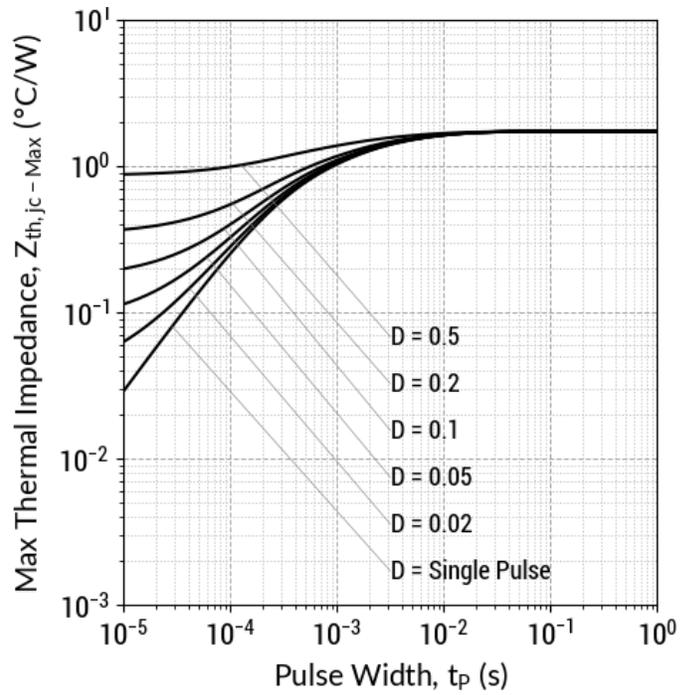
$f = 500 \text{ KHz}; V_{AC} = 25\text{mV}$

Fig 13: Output Capacitor Stored Energy



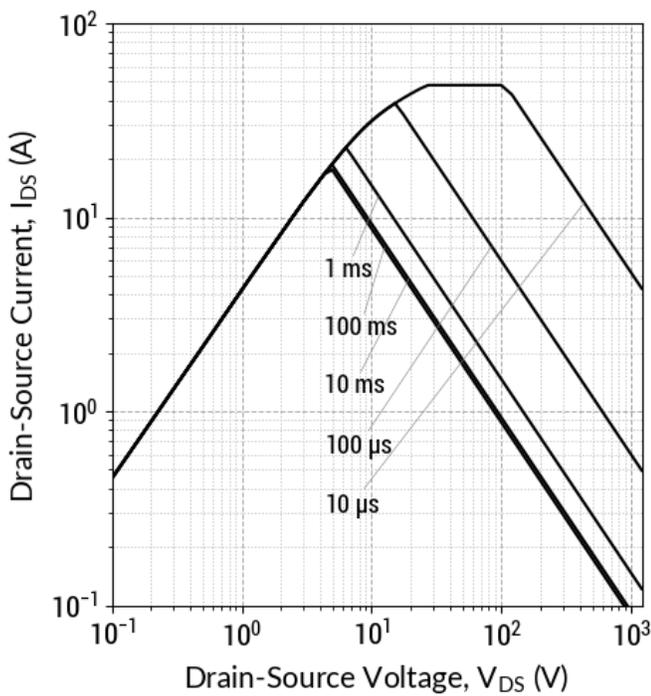
$E_{oss} = f(V_{DS})$

Fig 14: Max. Transient Thermal Impedance



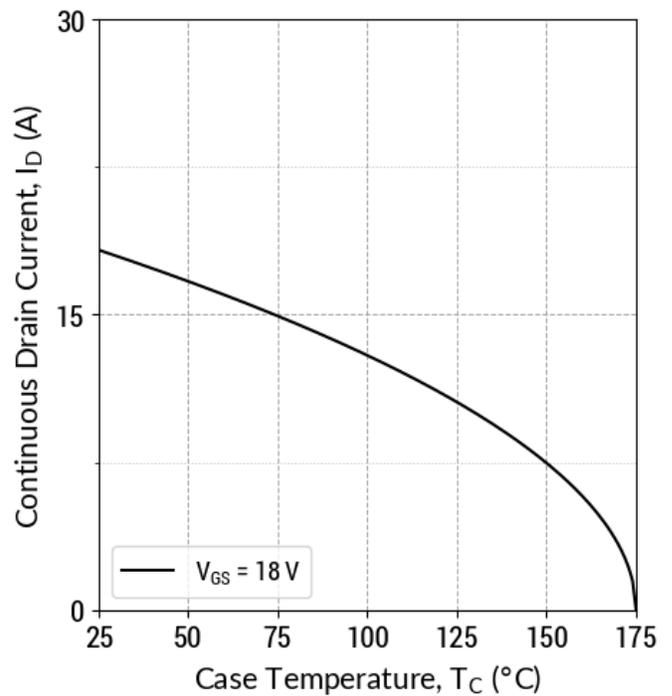
$Z_{th,jc} = f(t_p, D); D = t_p/T$

Fig 15: Safe Operating Area ( $T_c = 25^{\circ}C$ )



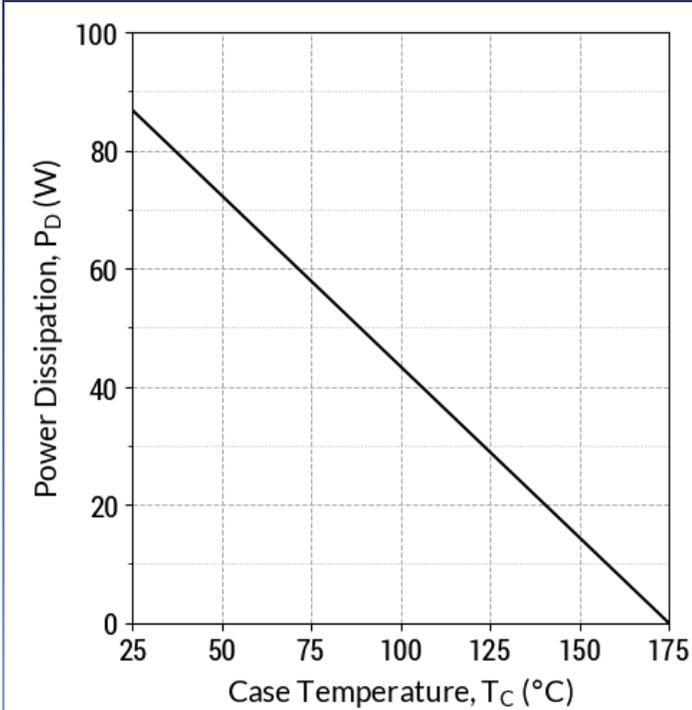
$I_D = f(V_{DS}, t_p); T_j \leq 175^{\circ}C; D = 0$

Fig 16: Current De-rating Curve



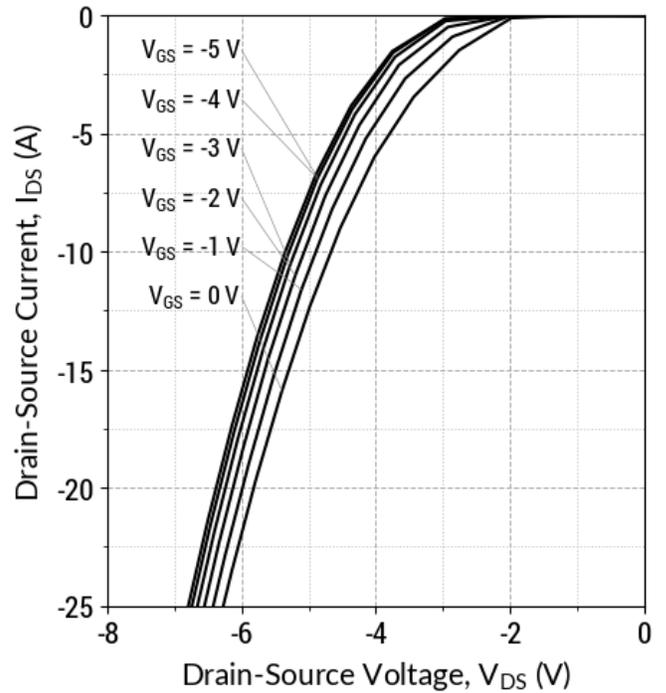
$I_D = f(T_c); T_j \leq 175^{\circ}C$

Fig 17: Power De-rating Curve



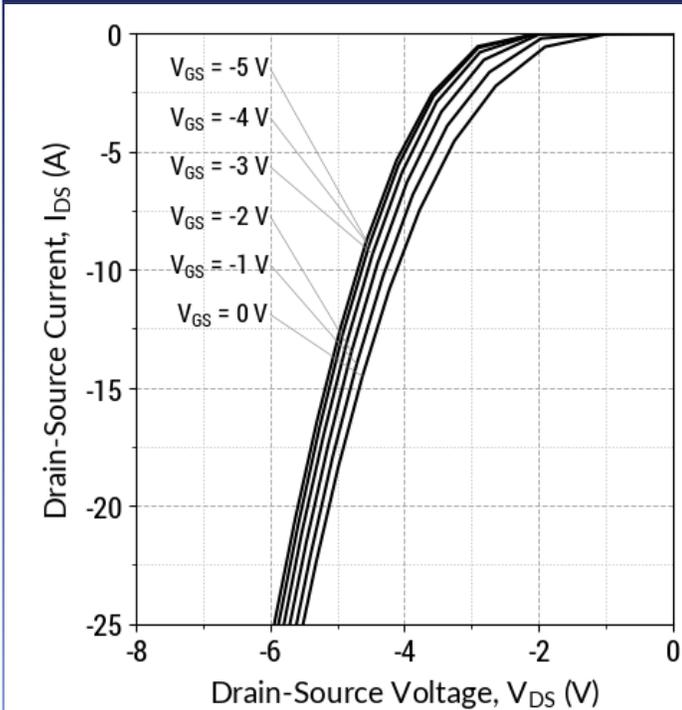
$P_D = f(T_C); T_j \leq 175^\circ\text{C}$

Fig 18: Typical Body Diode Characteristics (T<sub>j</sub> = 25°C)



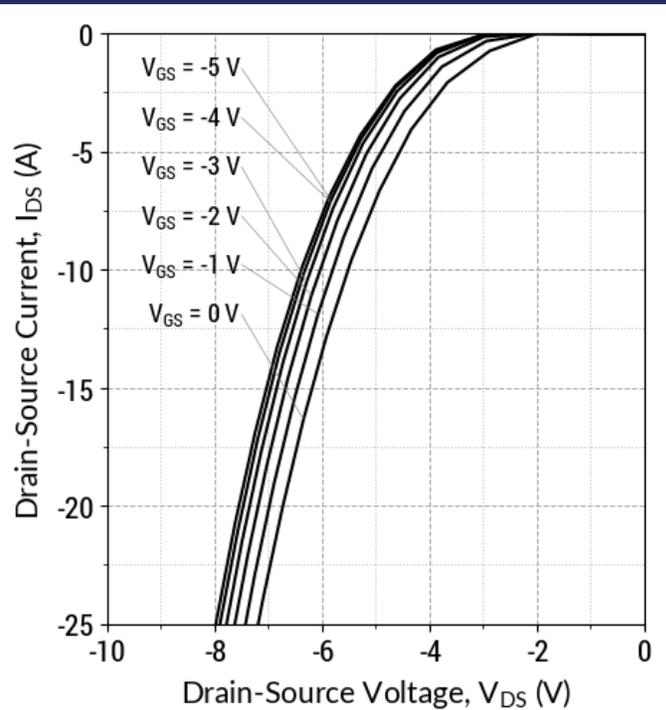
$I_D = f(V_{DS}, V_{GS}); t_P = 50 \mu\text{s}$

Fig 19: Typical Body Diode Characteristics (T<sub>j</sub> = 175°C)



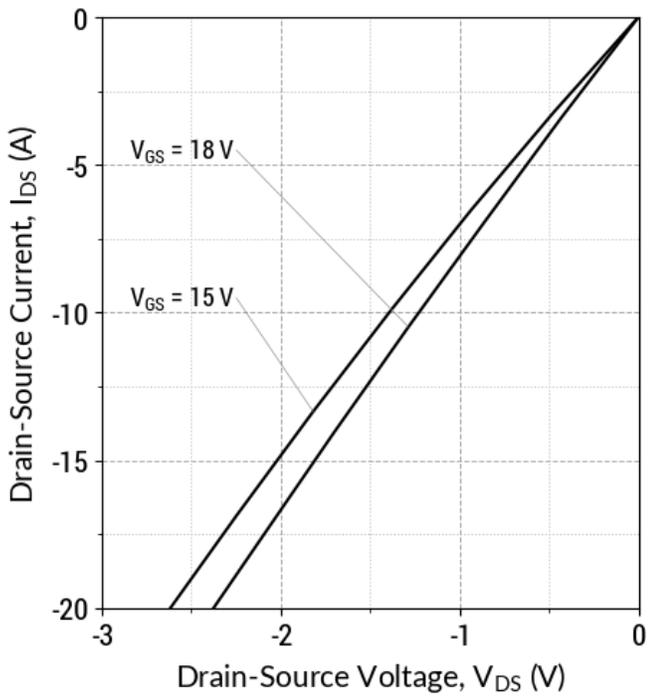
$I_D = f(V_{DS}, V_{GS}); t_P = 50 \mu\text{s}$

Fig 20: Typical Body Diode Characteristics (T<sub>j</sub> = -55°C)



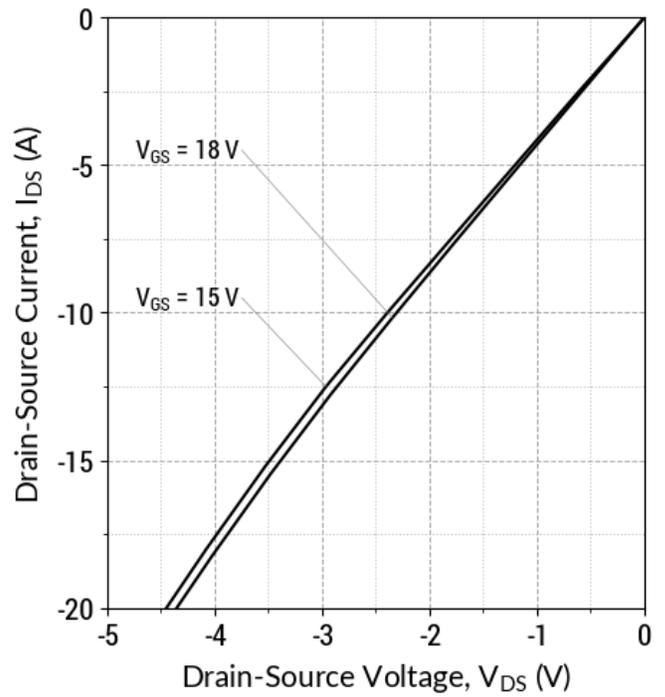
$I_D = f(V_{DS}, V_{GS}); t_P = 50 \mu\text{s}$

Fig 21: Typical Third Quadrant Characteristics ( $T_j = 25^\circ\text{C}$ )



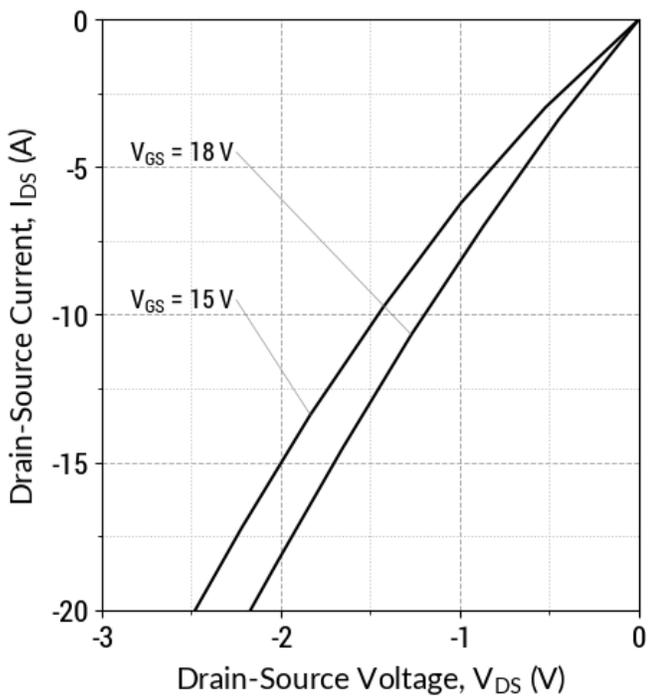
$I_D = f(V_{DS}, V_{GS}); t_P = 50 \mu\text{s}$

Fig 22: Typical Third Quadrant Characteristics ( $T_j = 175^\circ\text{C}$ )



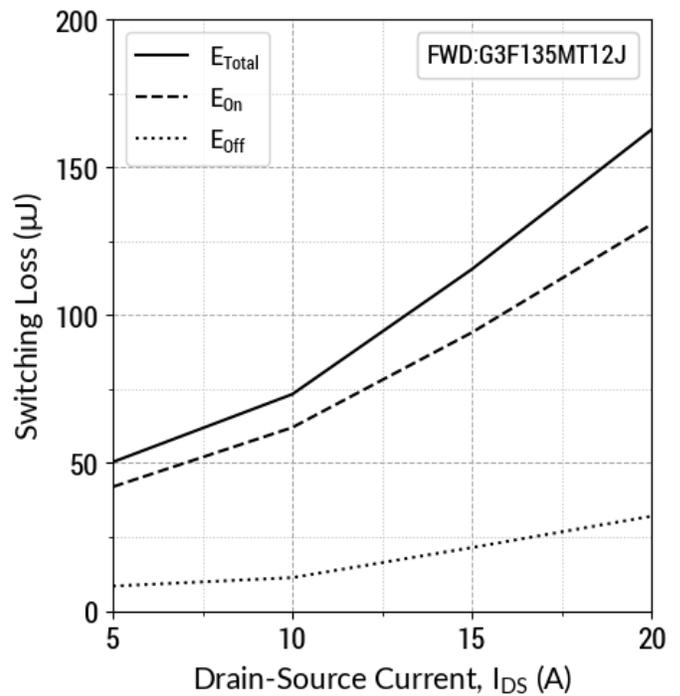
$I_D = f(V_{DS}, V_{GS}); t_P = 50 \mu\text{s}$

Fig 23: Typical Third Quadrant Characteristics ( $T_j = -55^\circ\text{C}$ )



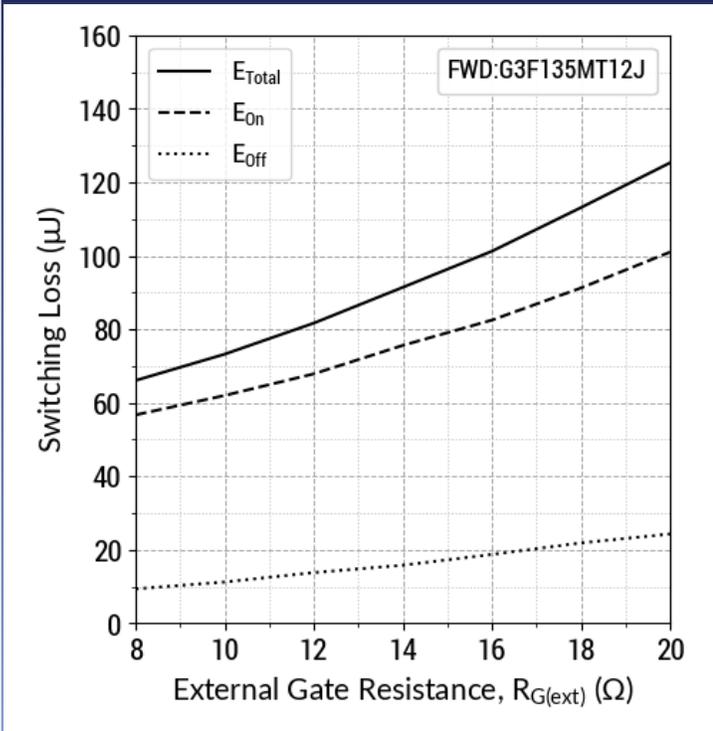
$I_D = f(V_{DS}, V_{GS}); t_P = 50 \mu\text{s}$

Fig 24: Inductive Switching Energy v/s Drain Current ( $V_{DD} = 800\text{V}$ )



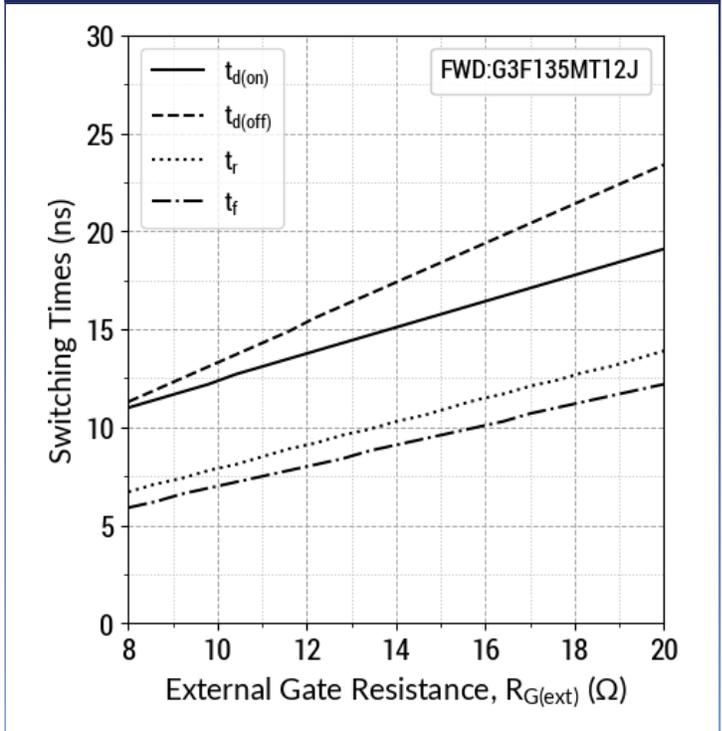
$T_j = 25^\circ\text{C}; V_{GS} = -5/+18\text{V}; R_{G(ext)} = 10 \Omega; L = 160.0 \mu\text{H}$

Fig 25: Inductive Switching Energy v/s  $R_{G(ext)}$   
( $V_{DD} = 800V$ )



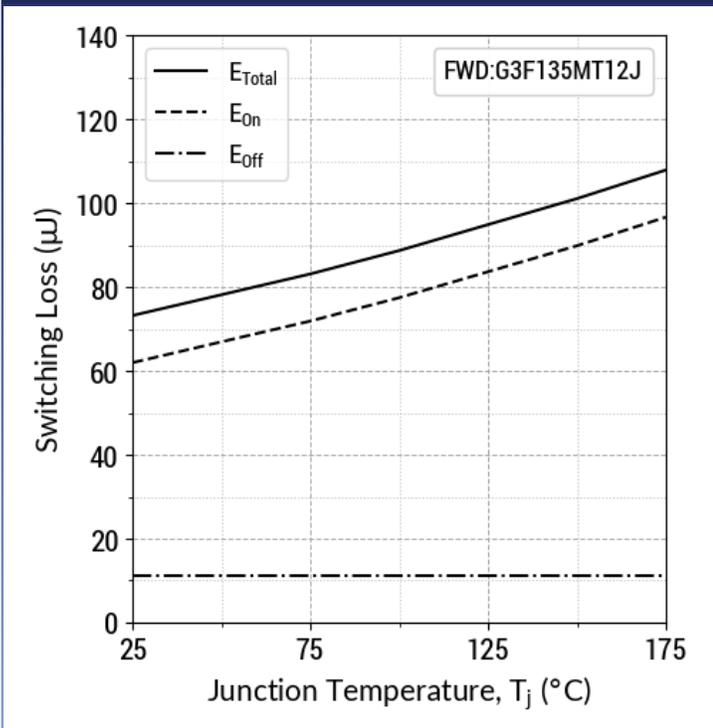
$T_j = 25^\circ C$ ;  $V_{GS} = -5/+18V$ ;  $I_{DS} = 8 A$ ;  $L = 160.0\mu H$

Fig 26: Switching Time v/s  $R_{G(ext)}$   
( $V_{DD} = 800V$ )



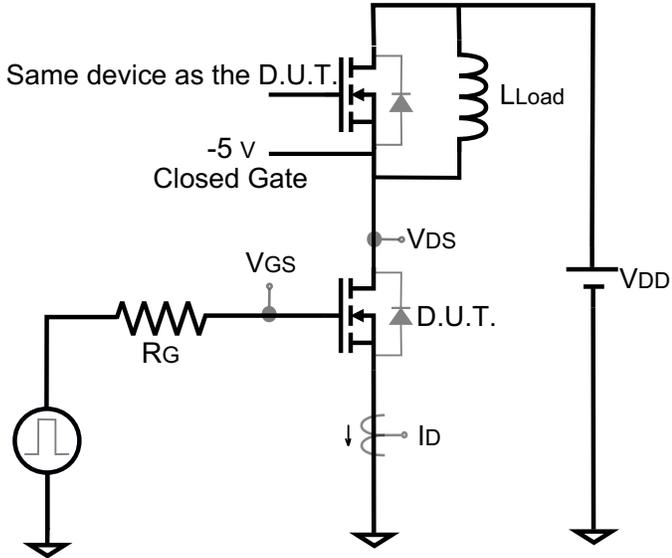
$T_j = 25^\circ C$ ;  $V_{GS} = -5/+18V$ ;  $I_{DS} = 8 A$ ;  $L = 160.0\mu H$

Fig 27: Inductive Switching Energy v/s Temperature  
( $V_{DD} = 800V$ )



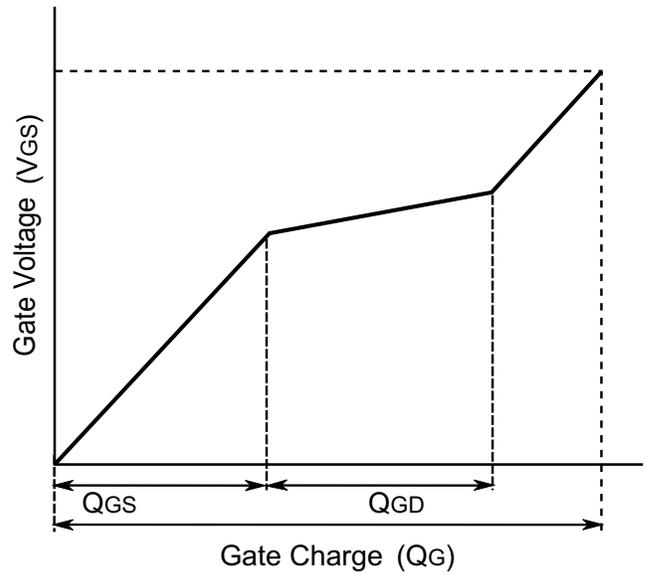
$T_j = 25^\circ C$ ;  $V_{GS} = -5/+18V$ ;  $R_{G(ext)} = 10 \Omega$ ;  $I_{DS} = 8 A$ ;  $L = 160.0\mu H$

Dynamic Test Circuit

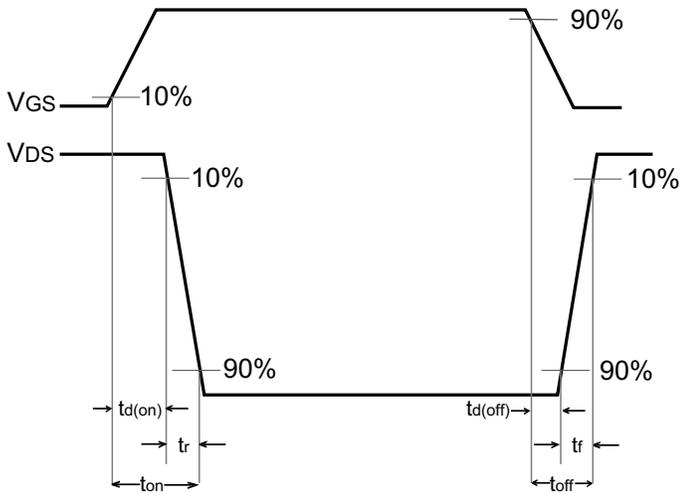


Note: Gate Charge, Switching Time and Energy Circuit

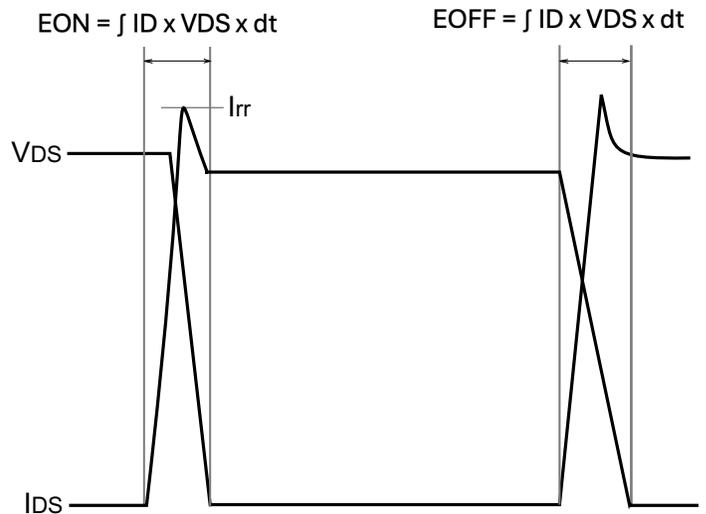
Gate Charge Waveform



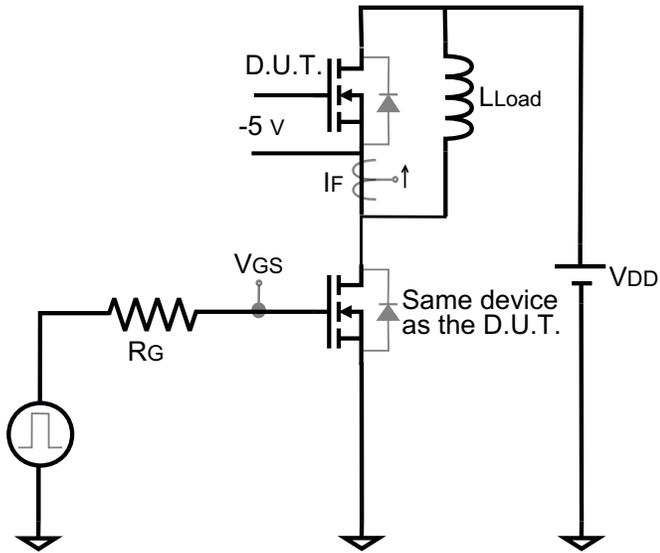
Switching Time Waveform



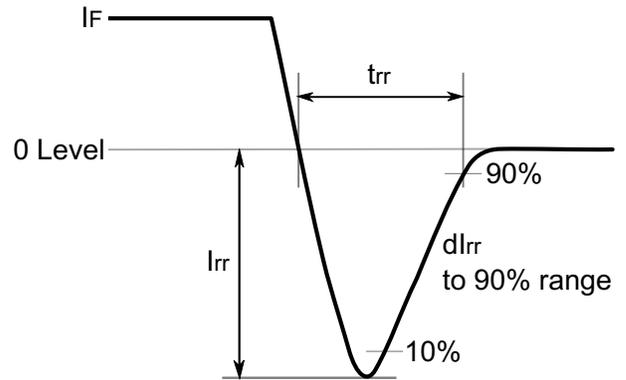
Switching Energy Waveform



Reverse Recovery Circuit

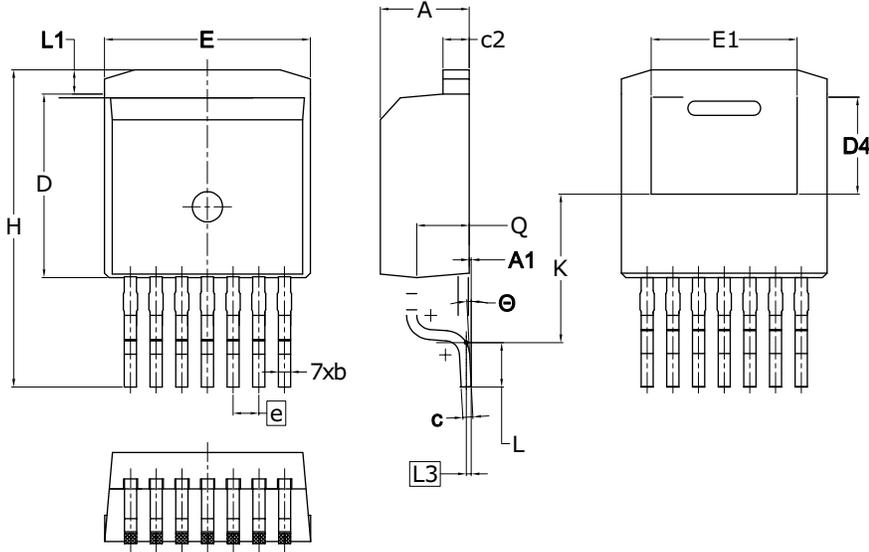


Reverse Recovery Waveform



Package Dimensions

TO-263-7 Package Outline



SYMBOL	DIMENSIONS	
	MIN.	MAX.
A	4.30	4.50
A1	0.00	0.25
b	0.50	0.70
c	0.45	0.60
c2	1.20	1.40
D	8.93	9.23
D4	4.65	4.95
E	10.08	10.28
E1	6.82	7.62
e	1.27 BSC	
H	15.00	16.00
K	7.30	
L	1.90	2.50
L1	1.00	1.40
L3	0.25 BSC	
Q	2.45	2.75
Θ	0°	7°

- Note:
1. All Dimensions Are In mm.
  2. Dimension D & E Do Not Include Mold Flash. These Dimensions Are Measured At The Outermost Extreme Of The Plastic Body.
  3. Thermal Pad Contour Optional Within Dimensions E, L1, D4 & E1.
  4. Dimension D4 & E1 Establish A Minum Mounting Surface for The Thermal Pad.
  5. ■ is Exposed Cu.
  6. There Is Exposed Cu and Molding Flash Bleeding At The Pin Which Is Close To Package.

NOTE

1. CONTROLLED DIMENSION IS MILLIMETER.
2. DIMENSIONS DO NOT INCLUDE END FLASH, MOLD FLASH, MATERIAL PROTRUSIONS.
3. THE SOURCE AND KELVIN-SOURCE PINS ARE NOT INTERCHANGABLE. THEIR EXCHANGE MIGHT LEAD TO MALFUNCTION.

## Revision History

- Rev 24/Aug: Initial Release (Rev 1.0)

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